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| Notice of References Cited | Application/Control No. 10/724,254 | Applicant(s)/Patent Under Reexamination BIEHLER ET AL. | |
| | Examiner Ben C. Wang | Art Unit 2192 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|-------------------|----------------|
| * | A | US-2005/0246682 a1 | 11-2005 | Hines, Kenneth J. | 717/109 |
| * | B | US-2004/0205702 a1 | 10-2004 | Logan et al. | 717/109 |
| * | C | US-2006/0150149 a1 | 07-2006 | Chandhoke et al. | 717/109 |
| * | D | US-6,041,178 | 03-2000 | Rybarczyk et al. | 717/109 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

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